

“A Monte Carlo model for studying the microheterogeneity of trace elements in reference materials by means of synchrotron microscopic X-ray fluorescence”. Kempenaers L, Janssens K, Vincze L, Vekemans B, Somogyi A, Drakopoulos M, Simionovici AS, Adams F, *Analytical chemistry* **74**, 5017 (2002). <http://doi.org/10.1021/AC025662G>